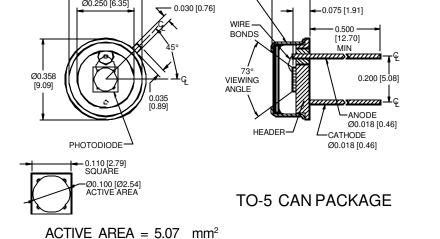
PHOTONIC Silicon Photodiode, U.V. Enhanced Photoconductive DETECTORS INC. Type PDU-C115-Q



Ø0.325 [8.25] QUARTZ WINDOW CAP (WELDED) Ø0.250 [6.35] 0.030 [0.76]



RESPONSIVITY (A/W)

FEATURES

- High speed
- U.V. enhanced
- Low capacitance
- Quartz window

DESCRIPTION

The **PDU-C115-Q** is a silicon, PIN planar diffused, U.V. enhanced photodiode. Ideal for high speed photoconductive applications. Packaged in a TO-5 metal can with a flat quartz window.

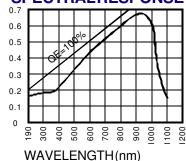
APPLICATIONS

- Spetrometers
- Fluorescent analysers
- U.V. meters
- Colorimeters

ABSOLUTE MAXIMUM RATING (TA=25°C unless otherwise noted)

SYMBOL	PARAMETER	MIN	MAX	UNITS
VBR	Reverse Voltage		30	V
T _{STG}	Storage Temperature	-55	+150	S
To	Operating Temperature Range	-40	+125	Ŷ
Ts	Soldering Temperature*		+240	°C
Ι	Light Current		500	mA

SPECTRALRESPONSE



*1/16 inch from case for 3 secs max

ELECTRO-OPTICAL CHARACTERISTICS (TA=25°C unless otherwise noted)

SYMBOL	CHARACTERISTIC	TESTCONDITIONS	MIN	TYP	MAX	UNITS				
lsc	Short Circuit Current	H = 100 fc, 2850 K	45	65		μA				
l d	Dark Current	$H = 0, V_{R} = 5 V$		1	5	nA				
Rsh	Shunt Resistance	$H = 0, V_{R} = 10 \text{ mV}$.25	1		GΩ				
TC Rsh	RSH Temp. Coefficient	$H = 0, V_{R} = 10 \text{ mV}$		-8		% / °C				
CJ	Junction Capacitance	$H = 0, V_{R} = 5 V^{**}$		40		pF				
λrange	Spectral Application Range	Spot Scan	190		1100	nm				
R	Responsivity	$V_{_{ m R}}$ = 0 V, λ = 254 nm	.12	.18		A/W				
VBR	Breakdown Voltage	I = 10 μA	15	25		V				
NEP	Noise Equivalent Power	VR = 10 mV @ Peak		1.4x10 ⁻¹⁴		W/ / Hz				
tr	Response Time	$RL = 1 K\Omega V_R = 5 V$		56		nS				

Information in this technical data sheet is believed to be correct and reliable. However, no responsibility is assumed for possible inaccuracies or omission. Specifications are subject to change without notice.**f=1 MHz [FORM NO. 100-PDU-C115-Q REV N/C]